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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT: NADIM JONI SHAH *ET AL.*

SERIAL NO. 09/742,470

FILED: DECEMBER 21, 2000

FOR: TECHNIQUE TO EXAMINE AN OBJECT)

ART UNIT: TO BE ASSIGNED

EXAMINER: TO BE ASSIGNED

Asst. Commissioner for Patents  
Washington, D.C. 20231

I HEREBY CERTIFY THAT THIS CORRESPONDENCE IS BEING DEPOSITED WITH THE UNITED STATES POSTAL SERVICE AS FIRST-CLASS MAIL IN AN ENVELOPE ADDRESSED TO: ASST. COMMISSIONER FOR PATENTS, WASHINGTON D.C. 20231 ON THIS

53rd DAY OF April 2001. BY: *Carrie A. McPherson*PRELIMINARY AMENDMENT

Sir:

Prior to fee calculation and examination please amend the above-identified application as follows.

In the Claims

Please cancel claims 1-8.

Please add the following new claims.

- Sub B1  
Q1
- 9. A process to examine at least one object, which comprises detecting properties of the object by various measurements within a spatial-frequency space formed by spatial frequencies, wherein said various measurements are taken in overlapping areas of the spatial-frequency space and in additional areas of the spatial-frequency space that differ from each other.
10. The process according to claim 9, wherein said measurements of the areas take place with at least three different detection rates of occurrence.
11. The process according to claim 9, wherein said areas that overlap cover a central region of the spatial-frequency space.
12. The process according to claim 9, wherein the additional areas in the spatial-frequency space are at a distance from each other that is greater than their spatial-frequent extension in the direction of this distance.